



03500.0179761

PATENT APPLICATION

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Application of: )  
Tetsuro NAKAMURA et al. ) : Examiner: Unassigned  
Application No.: 10/806,157 ) : Group Art Unit: 1753  
Filed: March 23, 2004 ) : Confirmation No.: 2170  
For: METHOD OF PRODUCING ) : August 30, 2004  
PHOTOVOLTAIC DEVICE ) :  
:

**Mail Stop Amendment**  
Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

INFORMATION DISCLOSURE STATEMENT

Sir:

In compliance with the duty of disclosure under 37 C.F.R. § 1.56 and in accordance with the practice under 37 C.F.R. §§ 1.97 and 1.98, the Examiner's attention is directed to the documents listed on the enclosed PTO-1449 form. Copies of the Japanese patent documents and of the Sannomiya et al. and Inoue et al. articles are also enclosed.

The Japanese patent documents are discussed at pages 3 to 5 of the specification. U.S. Patent Nos. 5,804,466, 6,660,931, and 6,465,727 are believed to be English-language counterparts of Japanese patent document numbers 10-140373, 2002-237606, and 2001-339079, respectively.

The Sannomiya et al. and Inoue et al. articles are discussed at page 3 of the subject specification.

The Examiner's attention is also directed to the following co-pending U.S. patent application. A copy of this application is also enclosed.

U.S. Patent Application No.

Filing Date

Applicants

10/833,125

April 28, 2004

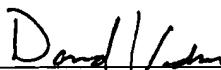
Takaharu Kondo et al.

Applicants request that the above information be considered by the Examiner and that a copy of the enclosed PTO-1449 form be initialed and returned indicating that such information has been considered.

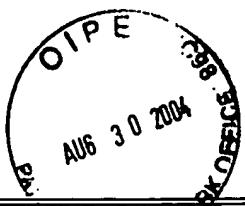
This Information Disclosure Statement is being filed before the issuance of a first Office Action on the merits. Therefore, no fee under 37 C.F.R. 1.97(c)(2) is believed due. Nevertheless, the Commissioner may charge Deposit Account No. 06-1205, should any fee be due for filing this paper.

Applicants' undersigned attorney may be reached in our Washington D.C. office by telephone at (202) 530-1010. All correspondence should continue to be directed to our address given below.

Respectfully submitted,

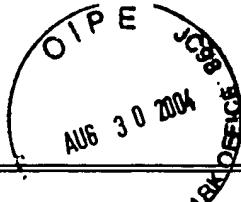
  
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FORM PTO 1449 (modified) U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE LIST OF REFERENCES CITED BY APPLICANT(S) (Use several sheets if necessary) August 30, 2004			ATTY DOCKET NO. 03500.017976		APPLICATION NO. 10/806,157		
			APPLICANT Tetsuro NAKAMURA et al.				
			FILING DATE March 23, 2004		GROUP 1753		
U.S. PATENT DOCUMENTS							
*EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
		US-6,465,727 B2	10/15/2002	Maruyama et al.	136	256	
		US-6,660,931 B2	12/09/2003	Toyama et al.	136	256	
		US-5,804,466	09/08/1998	Arao et al.	438	95	
		US-6,613,603 B1	09/02/2003	Sano	438	72	
		US-6,488,995 B1	12/03/2002	Nishimoto et al.	427	574	
		US-6,399,873 B1	06/04/2002	Sano et al.	136	249	
		US-6,303,945 B1	10/16/2001	Saito et al.	257	64	
		US-6,635,899 B2	10/21/2003	Saito et al.	257	64	
		US-6,344,608 B2	02/05/2002	Kariya et al.	136	257	
		US-6,653,165 B2	11/25/2003	Kondo et al.	438	73	
		US-6,706,336 B2	03/16/2004	Kondo et al.	427	588	
		US-6,172,296 B1	01/09/2001	Iwasaki et al.	136	256	
FOREIGN PATENT DOCUMENTS							
		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES/NO/ OR ABSTRACT
		4-119843	04/21/1992	Japan			Abstract
		3273294	02/01/2002	Japan			Abstract
		2002-237606	08/23/2002	Japan			Abstract
OTHER DOCUMENT(S) (Including Author, Title, Date, Pertinent Pages, Etc.)							
		<b>Sannomiya, H., et al., "a-SiC/a-Si/a-SiGe MULTI-BANDGAP STACKED SOLAR CELLS WITH BANDGAP PROFILING," Technical Digest of the International PVSEC-5, Kyoto, Japan, 1990. Energy Conversion Laboratories, SHARP Corp. Pp. 387-390.</b>					
EXAMINER				DATE CONSIDERED			

\*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.



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U.S. PATENT DOCUMENTS							
*EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
		<b>US-6,123,824</b>	<b>09/26/2000</b>	<b>Sano et al.</b>	<b>205</b>	<b>124</b>	
		<b>US-6,472,248 B2</b>	<b>10/29/2002</b>	<b>Shiozaki et al.</b>	<b>438</b>	<b>97</b>	
		<b>2003/0075717 A1</b>	<b>04/24/2003</b>	<b>Kondo et al.</b>	<b>257</b>	<b>64</b>	
		<b>2003/0104664 A1</b>	<b>06/05/2003</b>	<b>Kondo et al.</b>	<b>438</b>	<b>200</b>	
		<b>2003/0028486 A1</b>	<b>02/06/2003</b>	<b>Nakamura</b>	<b>705</b>	<b>50</b>	
		<b>2002/0117661 A1</b>	<b>08/29/2002</b>	<b>Kondo et al.</b>	<b>257</b>	<b>21</b>	
		<b>2003/0153165 A1</b>	<b>08/14/2003</b>	<b>Kondo et al.</b>	<b>438</b>	<b>478</b>	
		<b>2003/0019519 A1</b>	<b>01/30/2003</b>	<b>Toyama et al.</b>	<b>136</b>	<b>256</b>	
		<b>2002/0002993 A1</b>	<b>01/10/2002</b>	<b>Maruyama et al.</b>	<b>136</b>	<b>258</b>	
FOREIGN PATENT DOCUMENTS							
		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES/NO/ OR ABSTRACT
		<b>2001-339079</b>	<b>12/07/2001</b>	<b>Japan</b>			<b>Abstract</b>
		<b>2001-152930</b>	<b>06/05/2001</b>	<b>Japan</b>			<b>Abstract</b>
		<b>10-140373</b>	<b>05/26/1998</b>	<b>Japan</b>			<b>Abstract</b>
OTHER DOCUMENT(S) (Including Author, Title, Date, Pertinent Pages, Etc.)							
		<b>Inoue, Y., et al. "Optical confinement effect in a-SiGe solar cells on stainless steel substrates," 29p-MF-2, 51st Academic Lecture by the Applied Physics Society of Japan, Fall 1990. P. 747.</b>					
EXAMINER				DATE CONSIDERED			

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